

<b>Notice of References Cited</b>	Application/Control No. 10/525,862		Applicant(s)/Patent Under Reexamination VAN DE BEEK ET AL.	
	Examiner Ryan C. Jager		Art Unit 2816	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0053950	05-2002	Takeshita et al.	331/17
*	B	US-6,683,930	01-2004	Dalmia, Kamal	375/376
*	C	US-6,072,370	06-2000	Nakamura, Satoshi	331/25
*	D	US-6,642,747	11-2003	Chiu, Hon Kin	327/40
*	E	US-6,075,416	06-2000	Dalmia, Kamal	331/25
*	F	US-6,915,081	07-2005	Takeshita et al.	398/188
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2253316	02-1992	United Kingdom	Atkinson	H03D 13/00
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.